



Scanning Electron microscopy (SEM)





Scanning electron microscope (SEM)

- Well-focused (0.5-50 nm) electron beam
- Synchronized scanning on the surface of the sample and on the screen
- Image formation: the brightness of the points of the screen is modulated by the intensity of the response signals from the specimen











Response signals

- Back scattered electrons
- Secondary electrons
- Characteristic X-ray radiation
- Light
- Heat
- Specimen current





Specimen-beam interaction







Monte Carlo simulation







Secondary electrons







Detection of secondary electrons







Backscattered electrons







Detection of backscattered electrons







Detection of backscattered electrons







SE vs. BSE







Depth of focus









Vacuum

- Deposition of carbohydrogenes
- ionozation of gas moleculas cathode damage
- Sputtering





Charging, covering by metallic layer

- Samples which do not conduct electric current will charge
- Covering by thim metallic layer (Au, Ag, Pd)
- Carbon evaporation







































Carbides







Surface oxidation of steel







Surface oxidation of steel







Inclusion in steel







Inclusion in steel









Fractured surface SE - BSE







Fracture in-situ







Fracture in-situ







Fracture in-situ







Human hair







Human hair







Human hair







Tungsten spiral

